BSI TR-03105
Conformity Tests for Official Electronic ID Documents

Version 2.5
21.05.2010
## Revision history

<table>
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<tr>
<th>Version</th>
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<td>2.0</td>
<td>01.12.2008</td>
<td>• Publication of this document in version 2.0</td>
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| 2.1     | 14.09.2009 | • Added revision history
       |            | • Update Part 5.1 "Test plan for ICAO compliant Inspection Systems with EAC 1.11" to version 1.2 |
| 2.2     | 01.12.2009 | • Update name and version of Part 2 "Test Plan for Official Electronic ID Documents with Secure Contactless Integrated Circuit" to version 2.2 |
| 2.3     | 17.03.2010 | • Update Part 3.3 Version 1.0
       |            | • Add Part 3.4 eSign test specification
       |            | • Update Part 4 to Version 2.2 |
| 2.4     | 21.04.2010 | • Update Part 3.3 to Version 1.01
       |            | • Update Part 3.4 to Version 1.0 |
| 2.5     | 21.05.2010 | • Part 5.2 Version 1.0 published                                          |
1. Introduction

The greatest challenge impending with the introduction of electronic travel documents might be the safeguarding of the international interoperability of electronic passports and the associated reading devices.

To accommodate these factors the Federal Office for Information Security (BSI) has released the “Technical Guideline BSI-TR 03105 – ePassport Conformity Testing (TR-ePass)” in the year 2005. TR-ePass objects to provide test specifications ensuring the international interoperability of electronic travel documents.

About Version 2.0

As a result of advancement of the smart card and RFID technology and as a result of the experiences of the conformity tests of the accredited test houses, the need of adapting the test specifications to the current technical developments came up.

The parts of the TR-03105 were adapted and updated to these innovations. The structure of the TR-03105 was arranged more clearly. Due the need of comparability of the old version and this revised version the structure is similar in its main parts. Thus, the correlation of the parts for the old and the new version is possible.

With regard to the introduction of the electronic identity card (ePA / eID) the test specification for EAC 2.0 is already considered in the current version of the TR-03105. The extension of the TR-03105 toward eID cards required a change of name. The title "ePassport Conformity Testing (TR-ePass)" was replaced by the title "Conformity Testing for Official electronics ID document".

2. Structure of the TR

The BSI TR-03105 is divided into several partial documents. Each of them cover a subrange of the smart card and/or reader tests.

General part

- **Part 1.1**: „A framework for Official Electronic ID Document conformity tests“
  Version 1.04.1 - 18.11.2008

- **Part 1.2**: „Component Specification RFID“
  Version 1.02.1 - 14.11.2008

Chip Tests on Layers 1-4

- **Part 2**: „Test Plan for Official Electronic ID Documents with Secure Contactless Integrated Circuit“
  Version 2.2 - 01.12.2009

Chip Tests on Layers 6-7

- **Part 3.1**: „Test plan for Application Protocol and Logical Data Structure“
  Version 1.1.1 - 14.11.2008
• **Part 3.2**: „Test plan for eMRTDs with Advanced Security Mechanisms – EAC 1.11“  
  Version 1.12 - 03.10.2008

• **Part 3.3**: „Test plan for eID-Cards with Advanced Security Mechanisms – EAC 2.0“  
  Version 1.01 - 23.03.2010

• **Part 3.4**: „Test plan for eID-cards with eSign-application acc. to BSI TR-03117“  
  Version 1.0 - 01.04.2010

**Reader Tests on Layers 1-4**

• **Part 4**: „Test plan for ICAO compliant Proximity Coupling Device (PCD) on Layer 2-4“  
  Version 2.2 - 17.03.2010

**Reader Tests on Layers 6-7**

• **Part 5.1**: „Test plan for ICAO compliant Inspection Systems with EAC 1.11“  
  Version 1.2 - 11.09.2009

• **Part 5.2**: „Test plan for eID-Card compliant Reader Systems with EAC 2“  
  Version 1.0 - 20.05.2010

3. **Conformity Certification**

For the parts 2 to 5 an application for conformity certification can be submitted to the BSI.